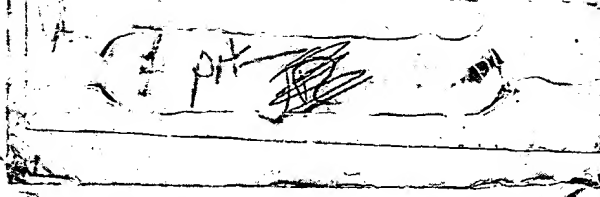


15903 U.S. PTO
09/819737
03/29/01

257	448
Class	Subclass
ISSUE CLASSIFICATION	



PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
FA SCANNED 043 O.A. <i>UB</i>	

APPLICATION NO. 09/819737	CONT/PRIOR F	CLASS 438 257	SUBCLASS 448	ART UNIT 282 260	EXAMINER SONAR
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APPLICANTS
Hirohito Ono
Masato Muraki

TITLE
Electrooptic system array, charged-particle beam exposure apparatus using the same, and device manufacturing method

PTO-2040
12/89

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
257	448	257	59	60	435	448	749	
INTERNATIONAL CLASSIFICATION								
H01L	29/04							
H01L	31/20							
H01L	31/00							
H01L	33/48							
H01L	29/40							

☐ Continued on Issue Slip Inside File Jacket

TERMINAL DISCLAIMER

DRAWINGS

CLAIMS ALLOWED

☐ a) The term of this patent subsequent to _____ (date) has been disclaimed.

☐ b) The term of this patent shall not extend beyond the expiration date of U.S. Patent No. _____

☐ c) The terminal _____ months of this patent have been disclaimed.

Sheets Drwg. Figs. Drwg. Print Fig.

19 46 1A

Total Claims Print Claim for O.G.

13 1

NOTICE OF ALLOWANCE MAILED

ISSUE FEE

Amount Due Date Paid

ISSUE BATCH NUMBER

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